

#### 30V N-CHANNEL ENHANCEMENT MODE MOSFET

#### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> max	I <sub>D</sub> max T <sub>A</sub> = 25℃
	$21m\Omega$ @ $V_{GS} = 10V$	7.3A
30V	$35m\Omega$ @ $V_{GS} = 4.5V$	5.5A

### **Description and Applications**

This MOSFET has been designed to minimize the on-state resistance  $(R_{DS(on)})$  and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Backlighting
- Power Management Functions
- DC-DC Converters

#### **Features and Benefits**

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- ESD Protected Gate
- "Green" component and RoHS compliant (Notes 1 & 2)
- Qualified to AEC-Q101 standards for High Reliability

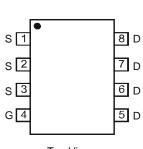
#### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.008 grams (approximate)

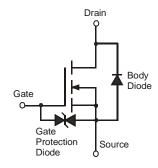




Top View



Top View Pin Configuration



**Equivalent Circuit Per Element** 

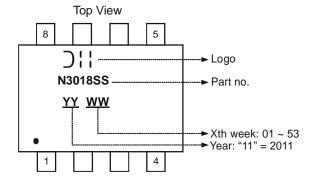
#### **Ordering Information (Note 3)**

Part Number	Case	Packaging
DMN3018SSS-13	SO-8	2500/Tape & Reel

Notes: 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. No purposely added lead. Halogen and Antimony free.

- 2. Diodes Inc.'s "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com.

## **Marking Information**





### Maximum Ratings @TA = 25℃ unless otherwise specified

Characteristic			Symbol	Value	Units
Drain-Source Voltage			$V_{DSS}$	30	V
Gate-Source Voltage			$V_{GSS}$	±25	V
Continuous Drain Current (Note 5) / 40/	Steady State	$T_A = 25^{\circ}C$ $T_A = 70^{\circ}C$	I <sub>D</sub>	7.3 5.7	Α
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	t<10s	T <sub>A</sub> = 25°C T <sub>A</sub> = 70°C	I <sub>D</sub>	9.7 7.8	А
Continuous Drain Current (Note 5) // 45/	Steady State	$T_A = 25$ °C $T_A = 70$ °C	I <sub>D</sub>	5.5 4.3	Α
Continuous Drain Current (Note 5) V <sub>GS</sub> = 4.5V	t<10s	$T_A = 25$ °C $T_A = 70$ °C	I <sub>D</sub>	7.6 5.8	Α
Pulsed Drain Current (10μs pulse, duty cycle = 1%)			I <sub>DM</sub>	60	А
Maximum Body Diode continuous Current			I <sub>S</sub>	2.5	Α

## Thermal Characteristics @TA = 25℃ unless otherwise specified

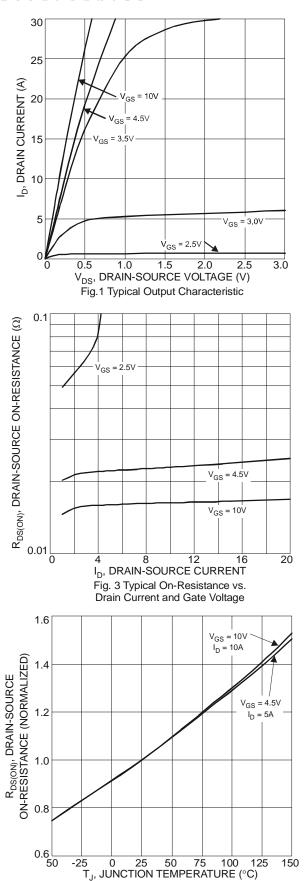
Characteristic	Symbol	Value	Units	
Total Bower Dissination (Note 4)	T <sub>A</sub> = 25℃	D-	1.4	W
Total Power Dissipation (Note 4)	T <sub>A</sub> = 70℃	P <sub>D</sub>	0.9	
Thermal Begistance, Junction to Ambient (Note 4)	Steady state	_	90	€\M
Thermal Resistance, Junction to Ambient (Note 4)	t<10s	$R_{\theta JA}$	50	€\M
Total Power Dissipation (Note 5)	T <sub>A</sub> = 25℃	Pn	1.7	W
Total Fower Dissipation (Note 3)	T <sub>A</sub> = 70℃	FD	1.1	
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	6	75	€/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{ heta JA}$	42	€\M
Thermal Resistance, Junction to Case (Note 5)	$R_{ heta JC}$	7.6	$\mathbb{C}$ $\mathbb{W}$	
Operating and Storage Temperature Range	$T_J,T_STG$	-55 to +150	${\mathfrak C}$	

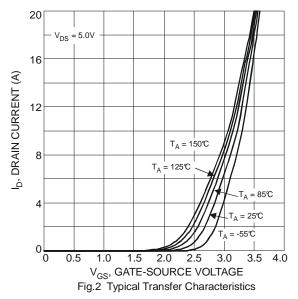
## Electrical Characteristics T<sub>A</sub> = 25°C unless otherwise specified

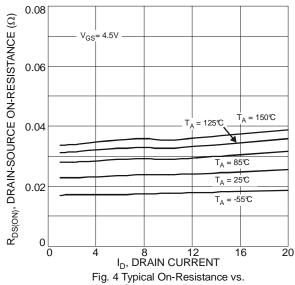
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 6)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	1	μΑ	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±10	μA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 6)	•	•	•	•	•		
Gate Threshold Voltage	V <sub>GS(th)</sub>	1	1.7	2.1	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	Б	-	15	21	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A	
Static Diani-Source On-Resistance	R <sub>DS</sub> (ON)	-	20	35		$V_{GS} = 4.5V, I_D = 8.5A$	
Forward Transfer Admittance	Y <sub>fs</sub>	-	8.3	-	S	$V_{DS} = 5V, I_{D} = 6.9A$	
Diode Forward Voltage	V <sub>SD</sub>	0.5	-	1.2	V	V <sub>G</sub> S = 0V, I <sub>S</sub> = 1A	
DYNAMIC CHARACTERISTICS (Note 7)		•			•		
Input Capacitance	C <sub>iss</sub>	-	697	-	pF	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1.0MHz	
Output Capacitance	Coss	-	97	-	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	67	-	pF		
Gate resistance	Rg	-	1.47	-	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	-	6.0	-	nC		
Total Gate Charge (V <sub>GS</sub> = 10V)	Qq	-	13.2	-	nC	$V_{GS} = 10V, V_{DS} = 15V,$ $I_{D} = 9A$	
Gate-Source Charge	Q <sub>gs</sub>	-	2.2	-	nC		
Gate-Drain Charge	Q <sub>qd</sub>	-	1.8	-	nC		
Turn-On Delay Time	t <sub>D(on)</sub>	-	4.3	-	ns	$V_{DD} = 15V, V_{GS} = 10V,$ $R_{L} = 15\Omega, I_{D} = 1A, R_{G} = 6\Omega$	
Turn-On Rise Time	t <sub>r</sub>	-	4.4	-	ns		
Turn-Off Delay Time	t <sub>D(off)</sub>	-	20.1	-	ns		
Turn-Off Fall Time	t <sub>f</sub>	-	4.1	-	ns		
Reverse Recovery Time	T <sub>rr</sub>	-	7.3	-	ns		
Reverse Recovery Charge	Qrr	-	7.9	-	nC	$I_F = 9A$ , di/dt = 500A/ $\mu$ s	

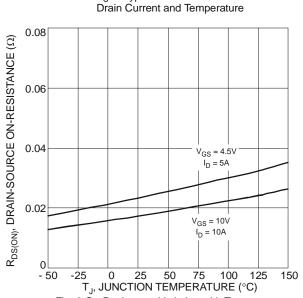
 Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 Short duration pulse test used to minimize self-heating effect.
 Guaranteed by design. Not subject to product testing. Notes:











125

Fig. 5 On-Resistance Variation with Temperature

150



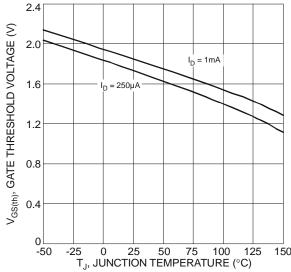


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

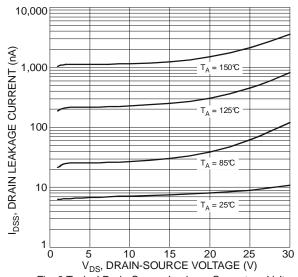
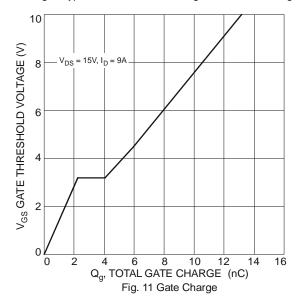
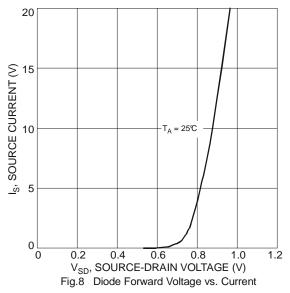
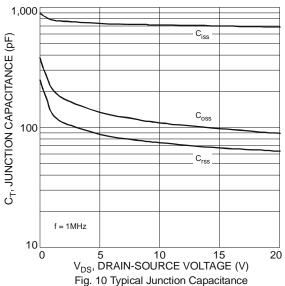


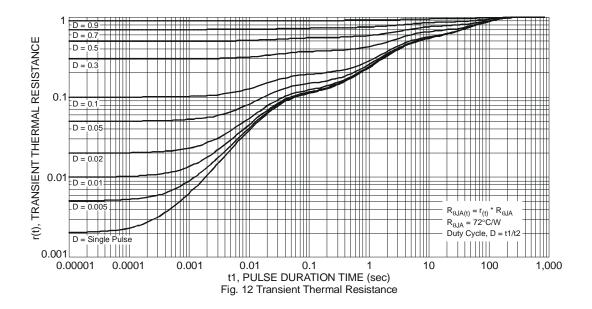
Fig. 9 Typical Drain-Source Leakage Current vs. Voltage



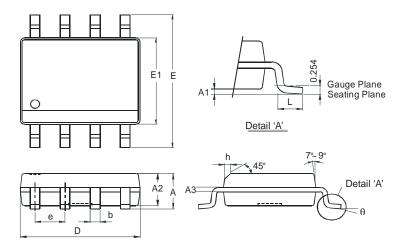






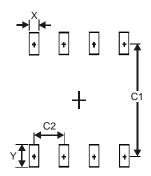


## **Package Outline Dimensions**



SO-8					
Dim	Min	Max			
Α	-	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
А3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					

# **Suggested Pad Layout**



Dimensions	Value (in mm)				
Х	0.60				
Υ	1.55				
C1	5.4				
C2	1.27				



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